

## IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Patent Application Serial No. .... 09/730,335  
Filing Date ..... December 4, 2000  
Inventor ..... Charles H. Dennison  
Assignee ..... Micron Technology, Inc.  
Group Art Unit ..... 2811  
Examiner ..... Ori Nadav  
Attorney Docket No. .... M122-1577  
Customer No. .... 021567  
Title ..... Field Effect Transistors and Integrated Circuitry

SUPPLEMENTAL INFORMATION DISCLOSURE STATEMENT

References -- See Attached Form PTO-1449

The attached form PTO-1449 is submitted in compliance with 37 CFR §1.56. Copies of the cited art are included. No admission is made regarding whether all the submitted references are prior art.

Respectfully submitted,

Dated: 11-14-03By:   
Mark S. Matkin  
Reg. No. 32,268

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Form PTO-1449

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ATTY. DOCKET NO.  
MI22-1577SERIAL NO.  
09/730,335

APPLICANT: Charles H. Dennison

FILING DATE  
December 4, 2000GROUP  
2811

## U.S. PATENT DOCUMENTS

*Examiner's Initials	Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
AA	5,923,999	07/13/99	Balasubramanyam et al.			
AB						
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AE						
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AH						
AI						

## FOREIGN PATENT DOCUMENTS

	Document Number	Date	Country	Class	Subclass	Translation	Yes	No
AJ	JP63012132	01/19/88	Japan (Sumi et al.)			Abstract		
AK	JP63012152	01/19/88	Japan (Tsukamoto et al.)			Abstract		
AL	JP8017758	01/19/96	Japan (Tawara)			Abstract & machine		

## OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)

AM								
AN								
AO								
EXAMINER	DATE CONSIDERED							

\*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

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<small>500 14 2000</small>		ATTY. DOCKET NO. MI22-1577	SERIAL NO. 09/730,335
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						Yes	No
AJ	JP8279553	10/22/96	Japan (Fujiwara)			Abstract & machine	
AK	JP10093077	04/10/98	Japan (Tsukamoto)			Abstract & machine	
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## OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)

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AM	J. Nulman, B. Cohen, and K. Ngan, "Titanium Silicide and Titanium Nitride Layers Formed in an integrated Multichamber System", Proc. VMIC Conference (1991), pp. 312-315.
AN	William C. O'Mara, Robert B. Herring, and Lee P. Hunt, "Handbook of Semiconductor Silicon Technology", Noyes Publ., Norwich, New York (1990), p. 684.
EXAMINER	DATE CONSIDERED

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